

Data Sheet July 1999 File Number 1496.2

8A, 100V, 0.400 Ohm, P-Channel Power MOSFET

This P-Channel enhancement mode silicon gate power field effect transistor is designed for applications such as switching regulators, switching convertors, motor drivers, relay drivers, and drivers for high power bipolar switching transistors requiring high speed and low gate drive power. These types can be operated directly from integrated circuits.

Formerly developmental type TA17511.

Ordering Information

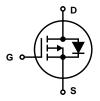
PART NUMBER	PACKAGE	BRAND
RFP8P10	TO-220AB	RFP8P10

NOTE: When ordering, include the entire part number.

Features

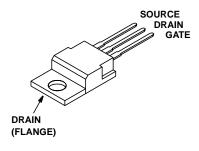
- 8A, 100V
- $r_{DS(ON)} = 0.400\Omega$
- · Related Literature
 - TB334 "Guidelines for Soldering Surface Mount Components to PC Boards"

Symbol



Packaging

TO-220AB



RFP8P10

Absolute Maximum Ratings $T_C = 25^{\circ}C$, Unless Otherwise Specified

	RFP8P10	UNITS
Drain to Source Voltage (Note 1)	-100	V
Drain to Gate Voltage (R _{GS} = $20k\Omega$) (Note 1)	-100	V
Continuous Drain Current	8	Α
Pulsed Drain Current (Note 3)	20	Α
Gate to Source Voltage	±20	V
Maximum Power Dissipation	75	W
Linear Derating Factor	0.6	W/oC
Operating and Storage Temperature	-55 to 150	°C
Maximum Temperature for Soldering		
Leads at 0.063in (1.6mm) from Case for 10sTL	300	°C
Package Body for 10s, See Techbrief 334 ·	260	°C

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

1. $T_J = 25^{\circ}C$ to $125^{\circ}C$.

Electrical Specifications $T_C = 25^{\circ}C$, Unless Otherwise Specified

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Drain to Source Breakdown Voltage	BV _{DSS}	$I_D = -250\mu A, V_{GS} = 0$	-100			V
Gate Threshold Voltage	V _{GS(TH)}	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-2	-	-4	V
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = Rated BV _{DSS} , V _{GS} = 0V	-	-	1	μΑ
		$V_{DS} = 0.8 \text{ x Rated BV}_{DSS}, V_{GS} = 0 \text{V T}_{J} = 125^{\circ}\text{C}$	-	-	25	μΑ
Gate to Source Leakage Current	I _{GSS}	$V_{GS} = \pm 20V, V_{DS} = 0$	-	-	±100	nA
Drain to Source On Resistance (Note 2)	r _{DS(ON)}	I _D = 8A, V _{GS} = -10V (Figures 6, 7)	-	-	0.400	Ω
Drain to Source On Voltage (Note 2)	V _{DS(ON)}	I _D = 8A, V _{GS} = -10V	-	-	3.2	V
Turn-On Delay Time	t _{d(ON)}	$I_D \approx$ 4A, V_{DD} = 50V, R_G = 50 Ω , V_{GS} = -10V R_L = 12 Ω , (Figure 10)	-	18	60	ns
Rise Time	t _r		-	70	150	ns
Turn-Off Delay Time	t _{d(OFF)}		-	166	275	ns
Fall Time	t _f			94	175	ns
Input Capacitance	C _{ISS}	V _{GS} = 0V, V _{DS} = 25V, f = 1MHz (Figure 9)	-	-	1500	pF
Output Capacitance	C _{OSS}		-	-	700	pF
Reverse Transfer Capacitance	C _{RSS}			-	300	pF
Thermal Resistance, Junction to Case	R ₀ JC	RFP8P10	-	-	1.67	oC/W

Source to Drain Diode Specifications

PARAMETER	SYMBOL	TEST CONDITIONS	MIN	TYP	MAX	UNITS
Source to Drain Diode Voltage (Note 2)	V_{SD}	I _{SD} = -4A	-	-	-1.4	V
Diode Reverse Recovery Time	t _{rr}	$I_{SD} = -4A$, $dI_{SD}/dt = -100A/\mu s$	-	200	-	ns

NOTES:

- 2. Pulse Test: Pulse Width $\leq 300 \mu s$, Duty Cycle $\leq 2\%$
- 3. Repetitive rating: pulse width is limited by maximum junction temperature.

Typical Performance Curves

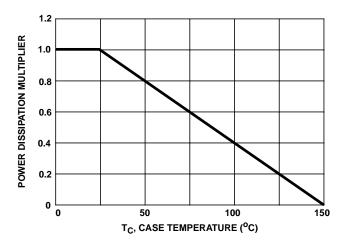


FIGURE 1. NORMALIZED POWER DISSIPATION vs CASE TEMPERATURE

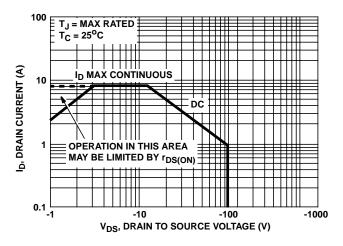


FIGURE 3. FORWARD BIAS SAFE OPERATING AREA

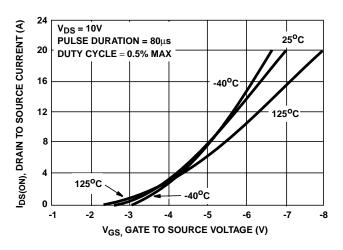


FIGURE 5. TRANSFER CHARACTERISTICS

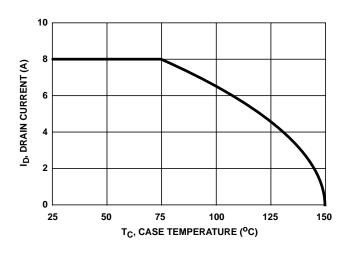


FIGURE 2. MAXIMUM CONTINUOUS DRAIN CURRENT vs CASE TEMPERATURE

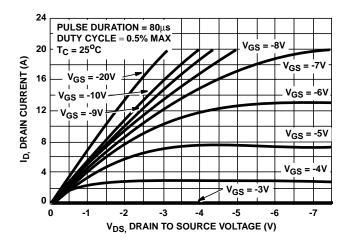


FIGURE 4. SATURATION CHARACTERISTICS

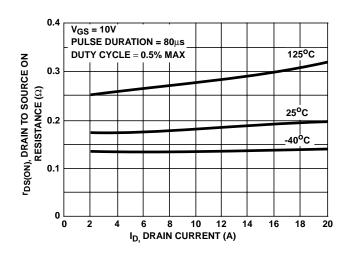


FIGURE 6. DRAIN TO SOURCE ON RESISTANCE VS DRAIN CURRENT

Typical Performance Curves (Continued)

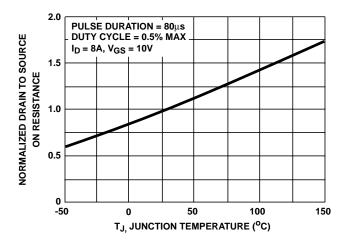


FIGURE 7. NORMALIZED DRAIN TO SOURCE ON RESISTANCE vs JUNCTION TEMPERATURE

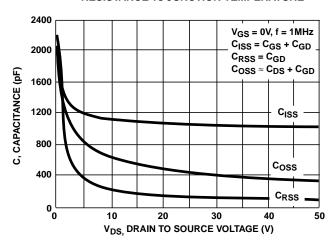


FIGURE 9. CAPACITANCE vs DRAIN TO SOURCE VOLTAGE

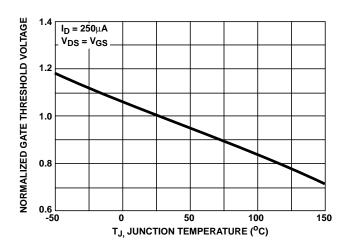
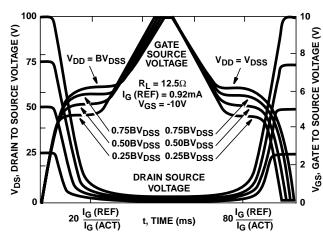


FIGURE 8. NORMALIZED GATE THRESHOLD VOLTAGE vs JUNCTION TEMPERATURE



NOTE: Refer to Intersil Applications Notes AN7254 and AN7260

FIGURE 10. NORMALIZED SWITCHING WAVEFORMS FOR CONSTANT GATE CURRENT

Test Circuits and Waveforms

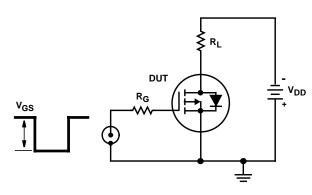


FIGURE 11. SWITCHING TIME TEST CIRCUIT

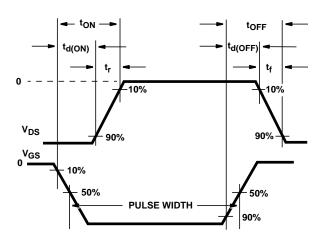
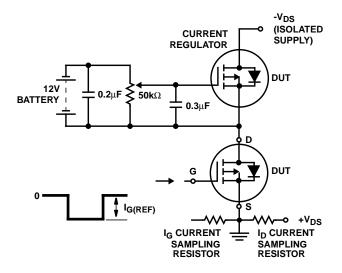


FIGURE 12. RESISTIVE SWITCHING WAVEFORMS

Test Circuits and Waveforms (Continued)





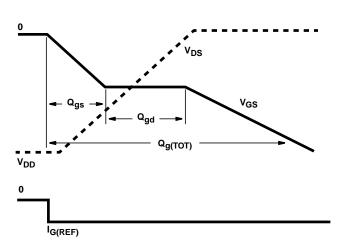


FIGURE 14. GATE CHARGE WAVEFORMS

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Intersil Corporation P. O. Box 883, Mail Stop 53-204 Melbourne, FL 32902

TEL: (407) 724-7000 FAX: (407) 724-7240 **EUROPE**

Intersil SA Mercure Center 100, Rue de la Fusee 1130 Brussels, Belgium TEL: (32) 2.724.2111

FAX: (32) 2.724.2111

ASIA

Intersil (Taiwan) Ltd. 7F-6, No. 101 Fu Hsing North Road

Taipei, Taiwan Republic of China TEL: (886) 2 2716 9310 FAX: (886) 2 2715 3029